

**Notice of References Cited**

Application/Control No.

10/577,645

Applicant(s)/Patent Under  
Reexamination  
HAYASHI ET AL.

Examiner

Liam J. Heincer

Art Unit

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Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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	C	US-			
	D	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002105240 A	04-2002	Japan	FUNAOKA et al.	
	O					
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**NON-PATENT DOCUMENTS**

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